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Paul et al.FILING DATE
HerewithGROUP
Unknown
2856

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
Dr	4,788,466	11/29/88	Paul et al.	310	323.06	
Dr	4,783,987	11/15/88	Hager et al.	73	32A	
Dr	5,416,448	5/16/95	Wessendorf	—	—	
Dr	5,201,215	4/13/93	Granstaff et al.	—	—	

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation Yes <input checked="" type="checkbox"/> No <input type="checkbox"/>
Dr	EP 0 215 669	9/16/86	EPO	—	—	
Dr	WO 89/09938	2/6/89	WIPO	—	—	
Dr	WO 96/35103	11/7/96	WIPO	—	—	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Dr	Barnes, "Development of quartz crystal oscillators for under-liquid sensing", Sensors and actuators A, 29 (1991) pgs. 59-69
Dr	Nakamoto et al., "Development of Circuit for Measuring both Q Variation and Resonant Frequency Shift of Quartz Crystal Microbalance", IEEE Transactions on Ultrasonics Ferroelectrics and Frequency Control, (1994) November, No. 6, pgs 806-811
Dr	Komplin et al., "A high-stability quartz crystal microbalance electrode for simultaneous solution-phase electrochemistry/microgravitometry", Rev. Science Instrument, 64 (6), June 1993, pgs 1530-1535
Dr	Chagnard et al., "An electronic oscillator with automatic gain control: EQCM applications", Elsevier Science S.A., 32 (1996) pgs 129-136
Dr	Rodahl et al., "Quartz crystal microbalance setup for frequency and Q-factor measurements in gaseous and liquid environments", Review of Scientific Instruments, 66 (1995) July, No. 7, pgs. 3924-3930

EXAMINER	DATE CONSIDERED
	4 Mar 2004

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.